

Eureka2 "MCP" LPDDR/NAND Tester

NEW!



CST Inc, a leading worldwide manufacturer of memory tester and automatic Handler is proud to introduce the new Eureka-II Memory Tester, specifically designed for Memory Design Engineers and Testing Lab.

The Eureka-II MCP Tester support the LP-DDR,LP-DDR2/ NAND Flash Chip testing at "Real Bus Speed" and "Real Cycle Time".

The Eureka-II MCP tester is designed and built with a flexible architecture which can support testing LP-DDR, LP-DDR2, LP-DDR3, NAND/NOR Flash memory chip with a change of optional Test Adapters.

Eureka2 MCP Feature

Auto Identify:

- Memory Type: LPDDR,LPDDR2 / NAND Flash
- Memory Configuration
- Memory Size
- Memory Frequency
- Memory Latency

Real Bus Speed Testing

- Real Cycle Time
- Super Fast Test time(1GB in 10secs)

Effective Test Algorithm

- Quick test, checks for assembly faults
- 20 Types of March test Pattern , to check for functional failures
- Fault Focusing pinpoints to faulty BGA chip
- Cross Talk Check
- DC Parametric/Leakage Test

Advance Feature.

- Intuitive User PC Interface Software
- User configurable Test Pattern
- Auto-Speed Sorting Tool for DRAM
- SHMOO-Plot and Error Mapping Tool
- Auto Timing Setup
- Current measurement
- Programmable LP-DDR AC Parameters

Ez Upgrading

- Firmware upgrade via internet
- Interface with PC software via USB Port

Eureka2 LP-DDR Technical Specification

Clock Frequency	: 100, 133,166 & 200 MHz selectable
Data-rate	: 200,266 ,333 & 400 MH
Data width	: Expandable 16,32,64 bit
Voltage range	: 1.3,1.4.1.5.1.6,1.7,1.8,1.9 to 2.0V
ICC measurement	: IDD 0 – IDD7
CAS Read Latency	: 2,3,4 Clocks
Trcd & Trp Adjustment	: 2,3,4 Clocks
Refresh Cycle	: Auto / Self Refresh
DC Parametric Testing	: +/- 1 uA to 5mA
DC Test Pattern	: Walk Data , Walk Address , DQS, DQM, CKE, CS and Leakage Test
AC Test Pattern	: Mat-S, March-C, March-X, March Y(23 Type March Pattern)

Eureka2 NAND Technical Specification

NAND Device	: Up to 64GB
Access Time	: 15, 20, 25 , 30 ns selectable
Page Size	: 2048 , 4096
Page Block	: 64,128,256,512,1024,2048,4096
Cell Type	: SLC , MLC & TLC
Data Bit	: 8 & 16 bit
Voltage range	: 1.8 – 3V
Flash Test Pattern	: Block Read, Block Write, Block Erase, Checker Board, Solid 1/0 , Solid 1, Solid 0

Eureka2 General Specification

Power Adapter	: 110/250 VAC 50Mhz ATX
PC (not included)	: AMD / INTEL
Operating System	: WIN XP, VISTA

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